


<b>Search Notes</b>  	<b>Application/Control No.</b>  09991834	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Tan, Alvin H	<b>Art Unit</b>  2173

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
715/745, 747, 760 (text search only - see search history printout)	10/15/04	AT
715/764, 864 (text search only - see search history printout)	5/19/05	AT
701/200, 208 (text search only - see search history printout)	10/15/04	AT
345/156, 168, 169 (text search only - see search history printout)	5/19/05	AT
709/203 (text search only - see search history printout)	5/19/05	AT
455/414.1, 414.3 (text search only - see search history printout)	5/19/05	AT
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	10/14/04	AT
Above - UPDATED	3/9/07	AT
NPL Search	10/14/04 (Updated 9/13/06)	AT (AT)

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner